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Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

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Substitute for form I449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	Based on 10/214,691
				Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
Sheet	1	of	12	Attorney Docket Number	0756-7218

U.S. PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
PL		5,686,328		Zhang et al.	11/11/97	
		5,763,899		Yamazaki et al.	06/09/98	
		5,782,665		Weisfield et al.	07/21/98	
		5,922,125		Zhang	07/13/99	
		6,083,801		Ohtani	07/04/00	
		5,744,822		Takayama et al.	04/28/98	
		5,744,824		Kousai et al.	04/28/98	
		5,766,977		Yamazaki	06/16/98	
		5,773,846		Zhang et al.	06/30/98	
		5,773,847		Hayakawa	06/30/98	
		5,773,327		Yamazaki et al.	06/30/98	
		5,795,795		Kousai et al.	08/18/98	
		5,808,321		Mitanaga et al.	09/15/98	
		3,890,632		Ham et al.	06/17/75	
		4,330,363		Biefesen et al.	05/18/82	
		4,466,073		Boyan et al.	08/14/84	
		5,543,636		Yamazaki	08/06/96	
		6,140,165		Zhang et al.	10/31/00	
		6,147,667		Yamazaki et al.	11/14/00	
		6,180,439 B1		Yamazaki et al.	01/30/01	
		5,929,527		Yamazaki et al.	07/27/99	
		5,949,107		Zhang	09/07/99	
		6,031,249		Yamazaki et al.	02/29/00	
		6,121,683		Yamazaki et al.	09/19/00	
		6,207,969 B1		Yamazaki et al.	03/27/01	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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		Japan J. Appl. Phys. 8 (1969) 1056, "Effect of Deposited Metals on the Crystallization Temperature of Amorphous Germanium Film," OKI et al.	
		Technology Information Association, "Thermo-Auto-Chrome Full Color Recording Technology," May 31, 1995	

Examiner Signature		Date Considered	8/23/05
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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PB		5,811,327		Funai et al.	09/22/98	
		5,818,076		Zhang et al.	10/06/98	
		5,821,138		Yamazaki et al.	10/13/98	
		5,824,574		Yamazaki et al.	10/20/98	
		6,175,348		Zhang et al.	01/16/01	
		5,728,259		Suzawa et al.	03/17/98	
		6,278,132 B1		Yamazaki et al.	08/21/01	
		5,818,076		Zhang et al.	10/06/98	
		3,389,024		Schimmer	06/18/68	
		3,783,049		Sandera	01/01/74	
		4,059,461		Fan et al.	11/22/77	
		4,068,020		Reuschel	01/10/78	
		4,132,571		Cuomo et al.	01/02/79	
		4,174,217		Flatley	11/13/79	
		4,226,898		Ovshinsky et al.	10/07/80	
		4,231,809		Schmidt	11/04/80	
		4,271,422		Ipri	06/02/81	
		4,277,884		Hsu	07/14/81	
		4,300,989		Chang	11/17/81	
		4,309,224		Shibata	01/05/82	
		4,331,709		Risch et al.	05/25/82	
		4,379,020		Glaeser et al.	04/05/83	
		4,409,724		Tasch, Jr., et al.	10/18/83	
		4,472,458		Sirinyan et al.	09/18/84	
		4,481,121		Barthel	11/06/84	
		4,534,820		Mori et al.	08/13/85	
		4,544,418		Gibbons	10/01/85	

FOREIGN PATENT DOCUMENTS						
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		Office ³	Number ⁴ Kind Code ³ (if known)			
		JP	07-335900	Teramoto Satoshi	12/22/95	Abst.
		JP	64-081324		03/27/89	Abst.

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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✓		IBM Technical Disclosure Bulletin, Vol. 11, No.7, A.R. Baker, Jr.	

Examiner Signature	<i>Fetsum Abraham</i>	Date Considered	8/28/05
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		Number	Kind Code ² (if known)			
PT		4,546,376		Nakata et al.	10/08/85	
		4,597,160		Ipri	07/01/86	
		4,634,473		Swartz et al.	01/06/87	
		4,735,824		Yamabe et al.	04/05/88	
		4,755,481		Faraone	07/05/88	
		4,911,781		Fox et al.	03/27/90	
		4,959,247		Moser et al.	09/25/90	
		4,959,700		Yamazaki	09/25/90	
		4,996,077		Mosiehi et al.	02/26/91	
		4,996,523		Bell et al.	02/26/91	
		5,043,224		Jaccodine et al.	08/27/91	
		5,075,259		Moran	12/24/91	
		5,089,441		Mosiehi	02/18/92	
		5,112,764		Mitra et al.	05/12/92	
		5,145,808		Sameshima et al.	09/08/92	
		5,147,826		Liu et al.	09/15/92	
		5,173,446		Asakawa et al.	12/22/92	
		5,200,630		Nakamura et al.	04/06/93	
		5,221,423		Sugino et al.	06/22/93	
		5,225,355		Sugino et al.	07/06/93	
		5,244,836		Lim	09/14/93	
		5,254,480		Tran	10/19/93	
		5,262,350		Yamazaki et al.	11/16/93	
		5,262,654		Yamazaki	11/16/93	
		5,275,851		Fonash et al.	01/04/94	
		5,278,093		Yonehara	01/11/94	
		5,289,030		Yamazaki et al.	02/22/94	
		5,296,405		Yamazaki et al.	03/22/94	
		5,298,075		Lagendijk et al.	03/29/94	
		5,308,998		Yamazaki et al.	05/03/94	
		5,313,075		Zhang et al.	05/17/94	
		5,352,291		Zhang et al.	10/04/94	
		5,354,697		Oostra et al.	10/11/94	
		5,358,907		Wong	10/25/94	
		5,366,926		Mei et al.	11/22/94	
		5,387,530		Doyle et al.	02/07/95	
		5,424,230		Wakai	06/13/95	

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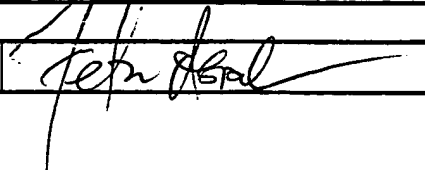
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				Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
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		Number	Kind Code ² (if known)			
PA		5,470,763		Hamada	11/28/95	
		5,480,811		Chiang et al.	01/02/96	
		5,504,019		Miyasaka et al.	04/02/96	
		5,508,207		Horai et al.	04/16/96	
		5,531,182		Yonehara	07/02/96	
		5,580,815		Hsu et al.	12/03/96	
		5,621,244		Yamazaki et al.	04/15/97	
		5,661,311		Takemura et al.	08/26/97	
		5,684,317		Hwang	11/04/97	
		5,684,365		Tang et al.	11/04/97	
		5,693,541		Yamazaki et al.	12/02/97	
		5,696,003		Makita et al.	12/09/97	
		5,717,224		Zhang	02/10/98	
		5,734,179		Chang et al.	03/31/98	
		5,773,327		Yamazaki et al.	06/30/98	
		5,786,796		Takayama et al.	07/28/98	
		5,821,560		Arai et al.	10/13/98	
		5,828,429		Takemura	10/27/98	
		5,838,508		Sugawara	11/17/98	
		5,843,225		Takayama et al.	12/01/98	
		5,846,857		Ju	12/08/98	
		5,849,611		Yamazaki et al.	12/15/98	
		5,882,960		Zhang et al.	03/16/99	
		5,888,858		Yamazaki et al.	03/30/99	
		5,895,933		Zhang et al.	04/20/99	
		5,899,547		Yamazaki et al.	05/04/99	
		5,929,464		Yamazaki et al.	07/27/99	
		5,933,205		Yamazaki et al.	08/03/99	
		5,940,732		Zhang	08/17/99	
		5,962,869		Yamazaki et al.	10/05/99	
		5,963,278		Yamazaki et al.	10/05/99	
		5,985,740		Yamazaki et al.	11/16/99	
		5,990,491		Zhang	11/23/99	
		5,990,542		Yamazaki	11/23/99	
		6,005,648		Zhang et al.	12/21/99	
		6,014,277		Yamazaki	01/04/00	

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		Number	Kind Code ² (if known)			
PA		6,013,929		Ohtani	01/11/00	
		6,048,758		Yamazaki et al.	04/11/00	
		6,063,654		Ohtani	05/16/00	
		6,077,731		Yamazaki et al.	06/20/00	
		6,093,934		Yamazaki et al.	07/25/00	
		6,100,562		Yamazaki et al.	08/08/00	
		RE 28,385		Mayer	04/08/75	
		RE 28,386		Heiman et al.	04/08/75	

FOREIGN PATENT DOCUMENTS							
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PA		EP	0 178 447			10/09/84	English
		JP	01-187814			07/27/89	Full
		JP	01-187874			07/27/89	Abst.
		JP	01-187875			07/27/89	Abst.
		JP	01-206632			08/18/89	Abst.
		JP	02-140915			05/30/90	Full
		JP	02-148687			06/07/90	Abst.
		JP	02-275641			11/09/90	Abst.
		JP	03-280418			12/11/91	Abst.
		JP	03-280420			12/11/91	Full
		JP	05-082442			04/02/93	Abst.
		JP	05-107561			04/30/93	Abst.
		JP	05-299348			11/12/93	Abst.
		JP	06-232059			08/19/94	Full
		JP	07-161634			06/23/95	Abst.
		JP	07-321339			12/08/95	Abst.
		JP	08-129358			05/21/96	Abst.
		JP	08-129359			05/21/96	Abst.
		JP	08-129360			05/21/96	Abst.
		JP	08-234683			09/13/96	Abst.
		JP	08-241047			09/17/96	Abst.
		JP	08-241048			09/17/96	Abst.
		JP	08-241057			09/17/96	Abst.
		JP	08-241997			09/17/96	Abst.
		JP	60-105216			06/10/85	Full
		JP	61-063017			04/01/86	Full
		JP	61-063107			04/01/86	Abst.
		JP	62-169356			07/25/87	Abst.

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FD		Caune et al., "Combined CW Laser and Furnace Annealing of Amorphous Si and Ge in Contact With Some Metals," January 1, 1989, pp. 597-604, Applied Surface Science, Vol. 36	
		Stoermnos et al., "Crystallization of Amorphous Silicon by Reconstructive Transformation Utilizing Gold," March 18, 1991, pp. 1196-1198, Appl. Phys. Lett. 58(11)	
		Kakkad et al., "Crystallized Si-Films By Low-Temperature Rapid Thermal Annealing of Amorphous Silicon," March 1, 1989, pp. 2069-2072, J. Appl. Phys. 65(5)	
		Oki et al., "Effect of Deposited Metals On The Crystallization Temperature of Amorphous Germanium Film," 1969, pp. 1056, Jpn. J. Appl. Phys. 8	
		Kuznetsov et al., "Enhanced Solid Phase Epitaxial Recrystallization of Amorphous Silicon Due to Nickel Silicide Precipitation Resulting From Ion Implantation and Annealing," 1993, pp. 990-993, Nucl. Instruments Methods Physics Research, 880/881	
		Hayashi et al., "Fabrication of Low-Temperature Bottom Gate Poly-Si TFTs on Large Area Substrate by Linear-Beam Excimer Laser Crystallization and Ion Doping Method," January 1, 1995, pp. 829-832, IEEE IEDM	
		Takenaka et al., "High Mobility Poly-Si Thin Film Transistors Using Solid Phase Crystallized a-Si Films Deposited by Plasma Enhanced Chemical Vapor Deposition," December 1990, pp. L2380-L2383, Jpn. J. Appl. Phys. Vol 29, No. 12	
		Hatalis et al., "High Performance Thin-Film Transistors in Low Temperature Crystallized LPCVD Amorphous Silicon Films," August 1987, pp. 361-364, Elec. Dev. Letters Vol. EDL 8, No. 8	
		Zorabedian et al., "Lateral Seeding of Silicon-on-Insulator Using an Elliptical Laser Beam: A Comparison of Scanning Methods," 1984, pp. 81-86, Mat. Res. Soc. Symp. Proc. Vol. 33	
		Green et al., "Method to Purify Semiconductor Wafers," October 1973, pp. 1612-1613, IBM Tech. Discl. Bulletin, Vol. 16, No. 5	
		Boyd, et al., "Oxidation of Silicon Surfaces by CO2 Lasers," July 15, 1982, pp. 162-164, Applied Phys. Letters, Vol. 41, No. 2	
✓		Wolf et al., "Silicon Processing for the VLSI Era Volume 1: Process Technology," 1986, pp. 215-216, Lattice Press	

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P		Lau et al., "Solid Phase Epitaxy in Silicide Forming System," 1977, pp. 313-322, Thin Solid Films, 47	
		Kawazu et al., "Low-Temperature Crystallization of Hydrogenated Amorphous Silicon Induced by Nickel Silicide Formation," December 1990, pp. 2698-2704, Inst. Of Appl. Phys. Vol. 29, No. 12	
		Wolf et al., "Silicon Processing for the VLSI Era Volume 1 - Process Technology," 1986, pp. 550-551, Lattice Press	
		Bruines et al., "Between Explosive Crystallization and Amorphous Regrowth: Inhomogeneous Solidification Upon Pulsed Laser Annealing of Amorphous Silicon," March 1, 1987, pp. 507-509, Applied Physics Letter, Vol. 50	
		Kawazu et al., "Initial Stage of the Interfacial Reaction between Nickel and Hydrogenated Amorphous Silicon," April 1, 1990, pp. 729-738, Japanese Journal of Appl. Phys., Vol.29	
		Kakkad et al., "Low Temperature Selective Crystallization of Amorphous Silicon," 1989, pp. 66-68, Journal of Non-Crystalline Solids, 115	
		Suresh et al., "Electroless Plated Nickel Contacts to Hydrogenated Amorphous Silicon," January 1, 1994, pp. 78-81, Thin Solids Films, Vol. 252	
		Sakaguchi et al., "Current Progress in Epitaxial Layer Transfer," March 1, 1997, pp. 378-387, IEICE Trans. Electron, Vol. E80 C/No. 3	
		Kouvatso et al., "Fluorine-Enhanced Oxidation of Polycrystalline Silicon and Application to Thin-Film Transistor Fabrication," August 24, 1992, pp. 937-939, Appl. Phys. Letter, Vol. 61, No. 8	
		Sze, "VLSI Technology," January 1, 1988, pp. 397-400, McGraw-Hill Publishing Company, Second Edition	
		Ghandhi, "VLSI Fabrication Principles," January 1, 1983, pp. 419-429, Wiley and Sons	
		Kuper et al., "Effects of Fluorine Implantation on the Kinetics of Dry Oxidation of Silicon," August 1, 1986, pp. 985-990, J. Applied Physics	
		Wolf et al., "Silicon Processing for the VLSI Era Volume 1: Process Technology," 1986, pp. 198-207, Lattice Press	

Examiner Signature	<i>Fetsum Abraham</i>	Date Considered	2/8/05
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				Application Number	Based on 10/214,691
				Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
				Attorney Docket Number	0756-7218
Sheet	8	of	12		

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁴	
7A		Thompson et al., "Silicide Formation in Pd-a-Si:H Schottky Barriers," August 1981, pp. 274-276, Appl. Phys. Lett., Vol. 39, No. 3		
		Nemanich et al., "Initial Phase Formation at the Interface of Ni, Pd, or Pt and Si," 1984, pp. unknown, Mat. Res. Soc. Symp. Proc., Vol. 25		
		Nemanich et al., "Structure and Growth of the Interface of Pd on a-SiH," June 15, 1981, pp. 6828-6831, The American Physical Society Physics Review, Vol. 22, No. 12		
		Hemple et al., "Needle-Like Crystallization of Ni Doped Amorphous Silicon Thin Film," 1993, pp. 921-924, Solid State Communications, Vol. 85, No. 11		
		Kuo, "Thin Film Transistor Technologies," Vol. 94-35, pp. 116-122, The Electrochemical Society Proceedings		
		Author Unknown, "Thermo Auto-Chrome Full Color Recording Technology," May 31, 1995, pp. Unknown, Technology Information Association		
		Wolf et al., "Thermal Oxidation of Single Crystal Silicon," 1986, pp. 207-211, Silicon Processing for the VLSI Era		
		Erokhin et al., "Spatially Confined Nickel Disilicide Formation at 400C on Ion Implantation Preamorphized Silicon," Dec. 6, 1993, pp. 3173-3175, Appl. Phys. Lett. 63 (23)		
		Dvurechenskii et al., "Transport Phenomena in Amorphous Silicon Doped by Ion Implantation of 3d Metals," 1986, pp. 635-640, Akademikian Lavrentev Prospekt 13, 630090 Novosibirsk 90, USSR		
		Batstone et al., "Microscopic Processes in Crystallization," January 1, 1994, pp. 257-268, Solid State Phenomena, Vol. 37-38		
		Cammarata et al., "Silicide Precipitation and Silicon Crystallization in Nickel Implanted Amorphous Silicon Thin Films," Oct 10, 1990, pp. 2133-2138, J. Mater. Res. Vol. 5, No. 10		
		Hayzelden et al., "Silicide Formation and Silicide Mediated Crystallization of Nickel-Implanted Amorphous Silicon Thin Films," May 15, 1993, pp. 8279-8289, J. Appl. Phys. 73(12)		

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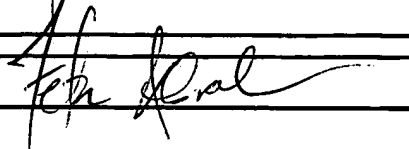
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				Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
Sheet	9	of	12	Attorney Docket Number	0756-7218

U.S. PATENT DOCUMENTS						
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		Number	Kind Code ² (if known)			
[Signature]		5,705,829		Miyana et al.	01/06/98	[Signature]
		5,712,191		Nakajima et al.	01/27/98	
		5,756,364		Tanaka et al.	05/26/98	
		5,619,044		Makita et al.	04/08/97	
		5,530,266		Yonehara et al.	06/25/96	
		5,550,070		Funai et al.	08/27/96	
		5,693,959		Inoue et al.	12/02/97	

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		Kuznetsov et al., "Silicide Precipitate Formation and Solid Phase Re-Growth of Ni-Implanted Amorphous Silicon," April 5-8, 1993, pp. 191-194, Inst. Phys. Conf. Ser. No. 134.4: Proceedings of Royal Microscopical Society Conf.	
		Liu et al., "Polycrystalline Silicon Thin Film Transistors on Corning 7059 Glass Substrates Using Short Time, Low-Temperature Processing," May 17, 1993, pp. 2554-2556, Appl. Phys. Lett 62(20)	
		Liu et al., "Selective Area Crystallization of Amorphous Silicon Films by Low-Temperature Rapid Thermal Annealing," August 14, 1989, pp. 660-662, Appl. Phys. Lett 55(7)	
		Spaepen et al., Metal-Enhanced Growth of Silicon, 1992, pp. 483-499, Crucial Issues in Semiconductor Materials & Processing Technologies	

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		Number	Kind Code ² (if known)			
Fetsum		5,403,772		Zhang et al.	04/04/95	
		5,426,064		Zhang et al.	06/20/95	
		5,481,121		Zhang et al.	01/02/96	
		5,488,000		Zhang et al.	01/30/96	
		5,492,843		Adachi et al.	02/20/96	
		5,501,989		Takayama et al.	03/26/96	
		5,508,533		Takemura	04/16/96	
		5,529,937		Zhang et al.	06/25/96	
		5,534,716		Takemura	07/09/96	
		5,543,352		Ohtani et al.	08/06/96	
		5,563,426		Zhang et al.	10/08/96	
		5,569,610		Zhang et al.	10/29/96	
		5,569,936		Zhang et al.	10/29/96	
		5,580,792		Zhang et al.	12/03/96	
		5,585,291		Ohtani et al.	12/17/96	
		5,589,694		Takayama et al.	12/31/96	
		5,595,923		Zhang et al.	01/21/97	
		5,595,944		Zhang et al.	01/21/97	
		5,604,360		Zhang et al.	02/18/97	
		5,605,846		Ohtani et al.	02/25/97	
		5,606,179		Yamazaki et al.	02/25/97	
		5,608,232		Yamazaki et al.	03/04/97	
		5,612,250		Ohtani et al.	03/18/97	
		5,614,426		Funada et al.	03/25/97	
		5,614,733		Zhang et al.	03/25/97	
		5,616,506		Takemura	04/01/97	
		5,620,910		Teramoto	04/15/97	
		5,621,224		Yamazaki et al.	04/15/97	
		5,624,851		Takayama et al.	04/29/97	
		5,637,515		Takemura	06/10/97	
		5,639,698		Yamazaki et al.	06/17/97	
		5,643,826		Ohtani et al.	07/01/97	
		5,646,424		Zhang et al.	07/08/97	
		5,654,203		Ohtani et al.	08/05/97	
		5,656,825		Kusumoto et al.	08/12/97	
		5,663,077		Adachi et al.	09/02/97	
		5,677,549		Takayama et al.	10/14/97	
		5,696,386		Yamazaki	12/09/97	
		5,696,388		Funada et al.	12/09/97	
		5,700,333		Yamazaki et al.	12/23/97	

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				Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
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U.S. PATENT DOCUMENTS					
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		Number	Kind Code ² (if known)		
FR		5,932,893		Miyanaga et al.	08/03/99
		4,759,610		Yanagisawa	07/26/88
		5,535,471		Guldi	07/16/96
		5,661,056		Takeuchi	08/26/97
		4,140,548		Zimmer	02/20/79
		5,210,050		Yamazaki et al.	05/11/93
		5,298,075		Lagendijk et al.	03/29/94
		5,306,651		Masumo et al.	04/26/94
		5,313,076		Yamazaki et al.	05/17/94
		5,365,080		Yamazaki et al.	11/15/94
		5,372,860		Fehlner et al.	12/13/94
		5,591,988		Arai et al.	01/07/97
		5,893,730		Yamazaki et al.	04/13/99
		5,913,111		Kataoka et al.	06/15/99
		5,953,597		Kusumoto et al.	09/14/99
		6,011,275		Ohtani et al.	01/04/00
		6,133,073		Yamazaki et al.	10/17/00

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FR		Wolf, <i>Silicon Processing for the VLSI Era</i> , Volume 2, Chapter 4, page 274 (1990).	

Examiner Signature	<i>Fetsum Abraham</i>	Date Considered	8/30/05
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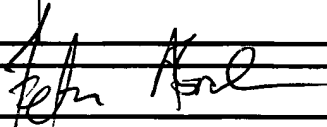
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		Number	Kind Code ² (if known)			
PR		6,225,152	BI	Yamazaki et al.	05/01/01	S
		6,288,412	BI	Hamada et al.	09/11/01	
		6,323,072	BI	Yamazaki et al.	11/27/01	
		6,331,718	BI	Yamazaki et al.	12/18/01	

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		Office ³	Number ⁴	Kind Code ⁵ (if known)				
		JP	06-314785			11/08/94		Ab
		JP	06-314787			11/08/94		Ab

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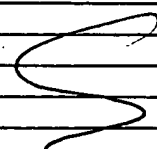
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary) NOV 15 2004 U.S. PATENT AND TRADEMARK OFFICE		Application Number	10/712,062
		Filing Date	November 14, 2003
		First Named Inventor	Shunpei YAMAZAKI et al.
		Group Art Unit	2826
		Examiner Name	F. Abraham
		Attorney Docket Number	0756-7218
Sheet 1	2		

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		Number	Kind Code ² (if known)			
Pp J		6,162,704		Yamazaki et al.	12/19/2000	
		6,294,441		Yamazaki	09/25/2001	
		6,461,943		Yamazaki et al.	10/08/2002	
		6,620,711		Yamazaki	09/16/2003	
		6,194,254		Takemura	02/27/2001	

FOREIGN PATENT DOCUMENTS								
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		Office ³	Number ⁴	Kind Code ⁵ (if known)				
Pp		JP	07-066425			03/10/1995		Abst. & U.S. Equiv.
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		JP	08-097169			04/12/1996		Abst. & U.S. Equiv.
		KR	96-005879			02/23/1996		U.S. Equiv.
		JP	07-045519			02/14/1995		Abst. & U.S. Equiv.
		JP	07-231100			08/29/1995		Abst. & U.S. Equiv.
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		Filing Date	November 14, 2003
		First Named Inventor	Shunpei YAMAZAKI et al.
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A		2002/0025659		Yamazaki et al.	02/28/2002	
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		6,423,586		Yamazaki et al.	07/23/2002	

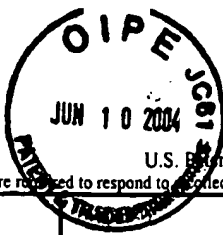
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JP		JP	07-192998			07/28/1995		Abst.
		JP	05-299339			11/12/1993		Abst. & U.S. Equiv.

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		6,006,763		Mori et al.	12/28/1999	
		4,086,020		Tanabe et al.	04/25/1978	

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				Filing Date	November 14, 2003
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2826
				Examiner Name	F. Abraham
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